

Amendments to the Specification:

Please replace paragraph [0085] of the published application
(note: the originally filed application did not contain this error found in the publication), with the following paragraph:

--In the example considered, two individual tests are carried out by the DIST-BIST module, and test result data and an item of test status data are generated for each individual test. These items of data each include one bit. Test result data with the value 0 indicates that the relevant test was not passed. Test result data with the value 1 indicates that the relevant test was passed successfully. Test status data with the value 0 indicates that the relevant test has not yet finished, and test status data with the value 1 indicates that the relevant test has finished.--

Please replace the paragraph beginning on page 40, line 1, with the following paragraph:

--In particular, each wafer carrier contains a contact-making device WK, the contact-making devices of all the wafer carriers are connected to a common control device CM that provides and generates the necessary voltages and signals. The control device CM is either transported together with the test box, or is connected to the contact-making devices WK via lines which are so long that the test box TB and the control device CM can be moved relative to each other. The simultaneous testing of the integrated circuits produced on a

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plurality of wafers makes it possible to reduce to a minimum
the number of control devices CM to be provided for this
purpose.--